PREFACE

This volume forms the Proceedings of the *XIV International Conference on Electron Microscopy (EM2011)* held in Wisła, Poland from 26 to 30 June 2011. The goal of the Conference was to provide a forum where researchers from different countries could exchange their last achievements in the field of structural studies with the use of electron microscopy techniques applied to many different materials. Plenary and invited lectures gave overviews on exciting new developments highlighting the application of the new electron microscopy techniques in physics, chemistry, materials science, life and earth science.

Above 160 delegates from all over the world (Austria, Belgium, Czech Republic, Denmark, France, Germany, Great Britain, Hungary, Japan, Holland, Slovakia, Spain, Ukraine and USA) participated in the EM2011. During the conference 13 oral sessions took place and 49 presentations were given basically on electron, holography, tomography, HREM, STEM, EBSD, ED and precession techniques as well as their application in material sciences and other related disciplines. After the reviewing process 77 were accepted for publication in this issue of the Solid State Phenomena.

Many distinguished specialists from different countries attended the Conference. Among them were Prof. Robert Sinclair, Prof. Rafal Dunin-Borkowski, dr Martin Hÿtch, Prof. Wolfgang Jaeger, dr Christoph Koch, Prof. Janos Labar, Prof. Michael Lehmann, Prof. Kenji Matsuda, Prof. Jean-Paul Morniroli, Prof. Wolfgang Neumann, Prof. Makoto Shiojiri, dr Debbie Stokes, dr Stefan Zaefferer and many more.

The Organising Committee paid special care to enable young scientists to participate in the Conference. This would not be possible without the financial support from different institutions and societies. Their support has been very much appreciated. Polish Society for Microscopy (PTMi), European Microscopy Society (EMS) as well as companies (JEOL, COMEF, MBSS) founded best abstract, best poster and best photo awards, sponsored social events and invited speakers. Special thanks are due to Ministry of Science and Higher Education and Polish Materials Society (PTM).

Furthermore, most of the cutting edge microscopy companies i.e. JEOL, COMEF (Hitachi), LABSOFT (FEI), ZEISS, OXFORD instruments, UNI-EXPORT (Tescan) MBSS (GATAN), AM Technologies Poland, EloService, NanoMegas installed and presented their new microscopes and other products in the conference booths.

The scientific success of this conference was first of all a result of the scientific motivation of its participants. Therefore I would like to thank all participants for their contributions. I would also like to thank the chairmen, who directed the programme in an efficient way, the international advisory board for the assistance in the Conference organization. Finally, I would like to thank all the team members for their efficiency and enthusiasm to make this Conference the success.

Danuta Mróż

Conference Photo